Using overlap GEM clusters to reconstruct Target Z





- To check the source of background in e-p yield
- To check the bump of e-p yield in lower scattering bin
- Using GEM overlap area e-p events
- Using two GEM clusters to find Z position

Target Z





Z vertex simulation



- simulation assume GEM resolution = 60 microns
- This setup only take into account the effect from GEM position resolution
- Assume beam incident angle is between 0.5 \sim $0.8~{\rm deg}$

Z vertex reconstruction vs simulation



Scaled by beam charge



 $\frac{integral of empty chamber}{integral of production} = 4.1\%$

Data drop: 55.1% Background drop: 73.3%

- Using GEM overlap area e-p events.
- Except carbon run, everything is scaled to equal beam charge.
- Carbon run was normalized to **1.1** GeV production run
- e-p scattering angle > 0.6 degree.

Target width



Overlapping area e-p yield



e-p yield in GEM overlap area

